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# Efficient Anchor Design for Quality Factor Enhancement in a Silicon Nitride-on-Silicon Lateral Bulk Mode Resonator

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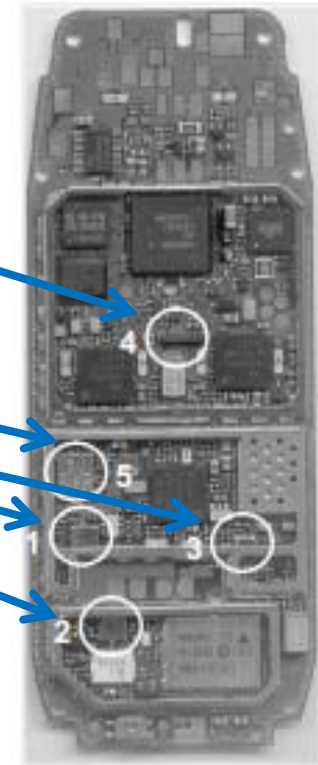
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# Outline

- **Introduction**
- **Resonator Design**
- **Analysis**
- **Simulation Results**
- **Conclusion**

# Introduction

- **Off-chip** passives in modern day wireless transceivers:
  - Tuning fork (quartz crystal) for standby clocking
  - **TCXO** clock reference
  - The RF and IF SAW Filters
- Features:
  - **High Quality Factor**
  - Stable over a wide temperature range
  - Low phase noise
- Drawbacks:
  - Ultimate **bottleneck in device miniaturization and portability**
  - Quartz is **incompatible with modern day VLSI technology processes**



Piezoelectric Components in a Typical Dual-Band GSM Handset\*

**Solution: On-chip silicon based micromechanical signal processors**

\*C.S.Lam ,” A Review of the Recent Development of MEMS and Crystal Oscillators and Their Impacts on the Frequency Control Products Industry,” IEEE Int’l Ultrasonics Symposium, Beijing, Nov. 2~5, 2008

# Quality Factor of MEMS Resonators

- Important design metrics: Operating frequency, motional impedance and **Quality Factor**

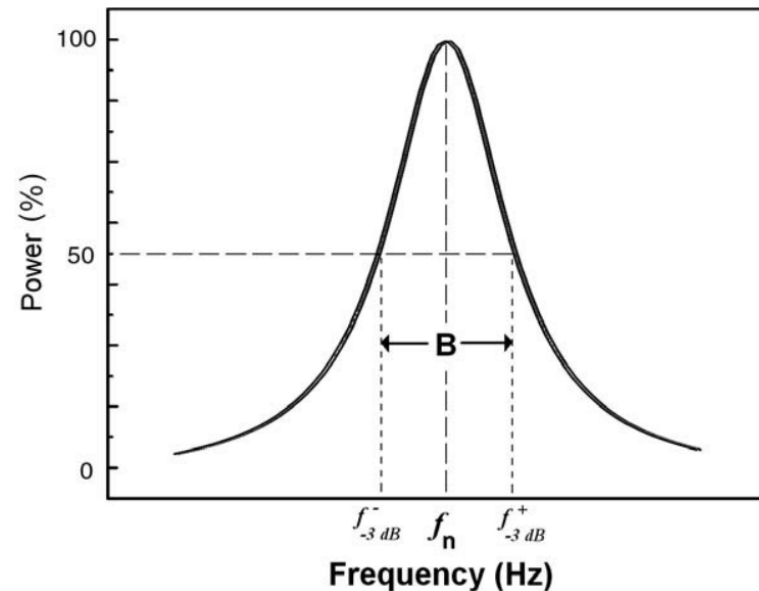
- Mathematically:-

$$Q = 2\pi \cdot \frac{\text{max. energy stored in one period}}{\text{energy dissipated per period}}$$

- **The Q-Factor is directly related to the energy retaining capability of a resonator in the presence of different loss mechanisms**

- Reasons for wanting a high Q-Factor\*:-

- Low power operation and high force sensitivity
- Low insertion loss
- High frequency selectivity



$f_n$  : resonant frequency

$B$  : bandwidth

$f_{-3dB}^-$   $f_{-3dB}^+$  : 3dB frequencies

**Very important for RF Applications**

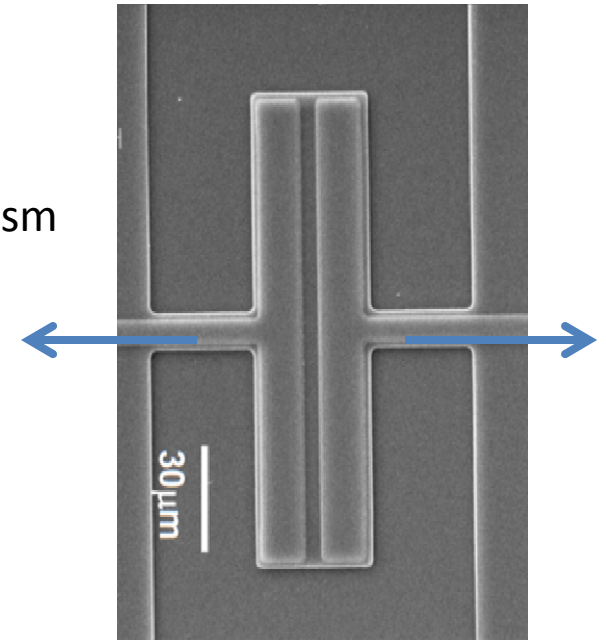
\*C. T.-C. Nguyen, "Advances in RF MEMS and MEMS-Based RF Front-End Architectures," TAPAS'06, 8/5/06

# Anchor Loss in MEMS Resonators

- Anchor Loss is prominent in high frequency Micromechanical resonators
- The source of this loss mechanism is the **acoustic energy leaking from a vibrating resonator through its anchors and into the substrate**
- Appropriate anchor design is of paramount importance in resonators where anchor loss is the dominant loss mechanism
- The **Perfectly Matched Layer (PML) Method** is the one that is used to model the energy loss through the anchors

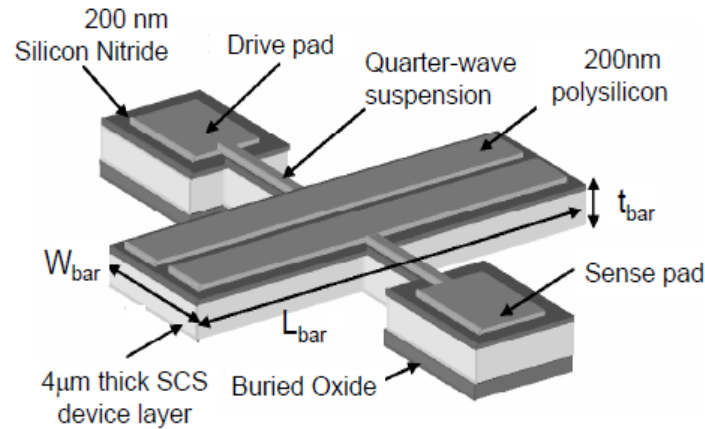
\*S.A.Bhave, R.T.Howe ,” **Silicon Nitride-on-Silicon Bar Resonator Using Internal Electrostatic Transduction,**” The 13th International Conference on Solid-State Sensors, Actuators and Microsystems, Seoul, Korea, June 5-9, 2005

**Wave Propagation**  
(Mechanical energy loss)



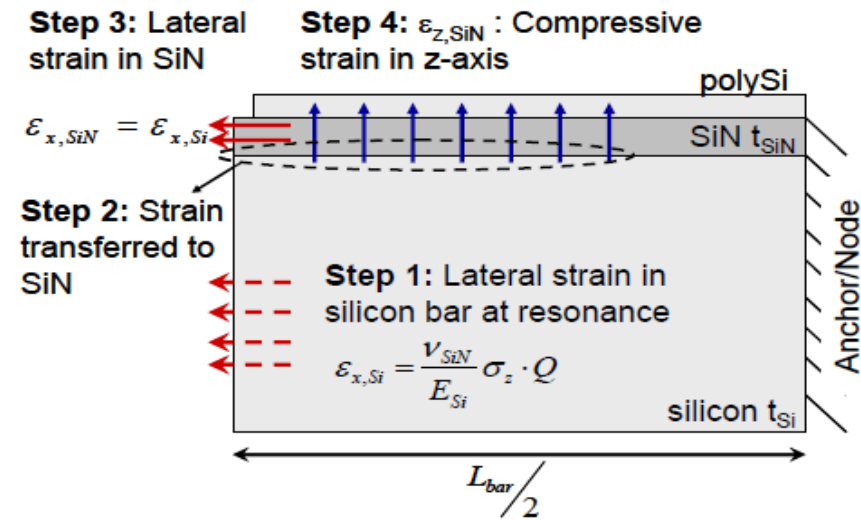
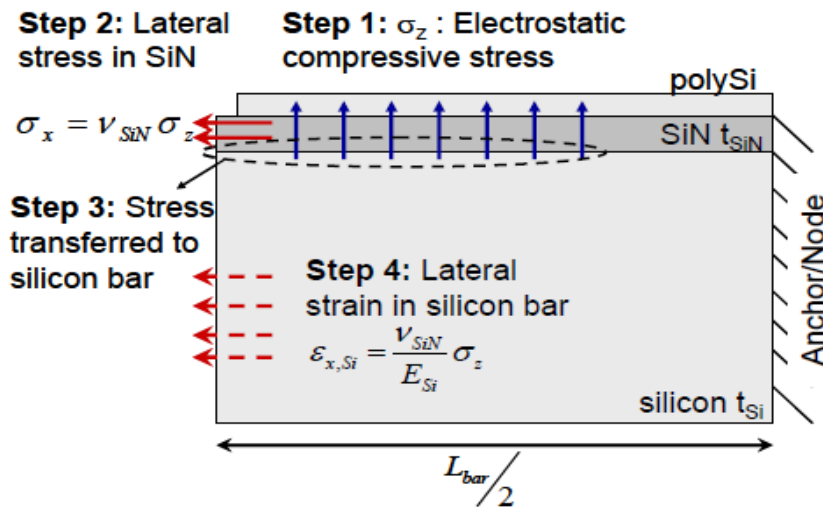
**SiN on Si Lateral Mode Bulk Resonator\***

# Silicon Nitride on Silicon Bar Resonator



## Dimensions:-

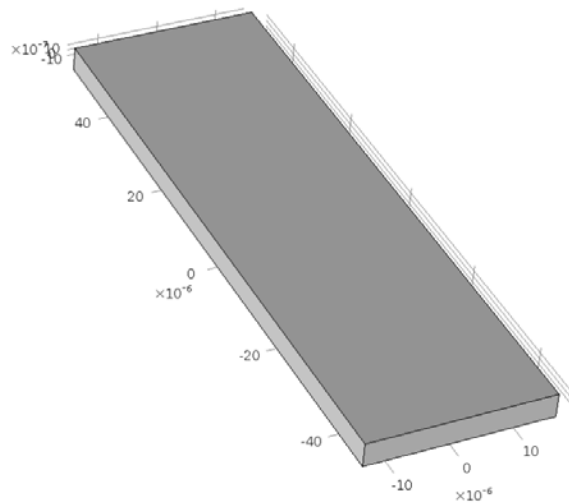
- $L_{\text{bar}} = 100\mu\text{m}$
- $W_{\text{bar}} = 30\mu\text{m}$
- $t_{\text{bar}} = 4\mu\text{m}$



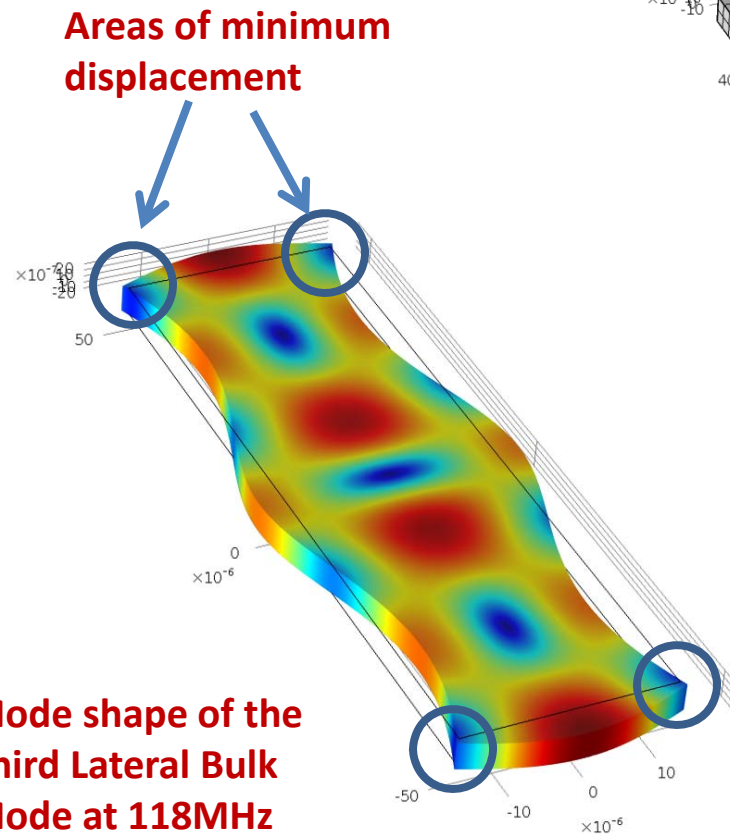
S.A.Bhave, R.T.Howe, "Silicon Nitride-on-Silicon Bar Resonator Using Internal Electrostatic Transduction," The 13th International Conference on Solid-State Sensors, Actuators and Microsystems, Seoul, Korea, June 5-9, 2005

# Modal Analysis

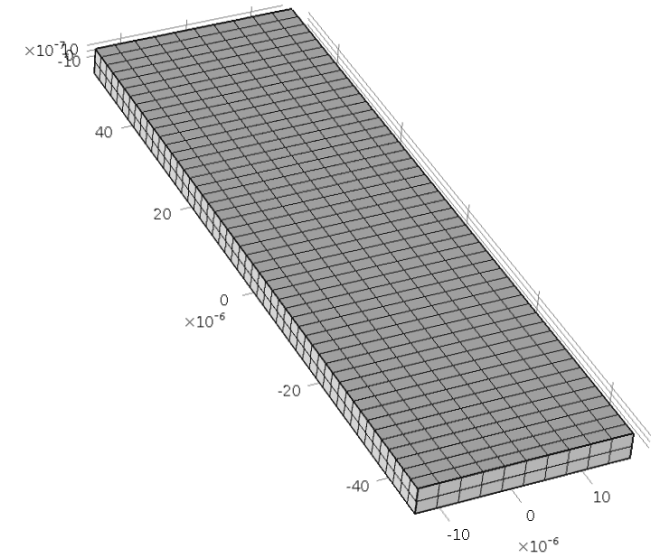
- Modal analysis was performed on the resonator body using the Eigenfrequency analysis of the Solid Mechanics module



**Geometric Model**



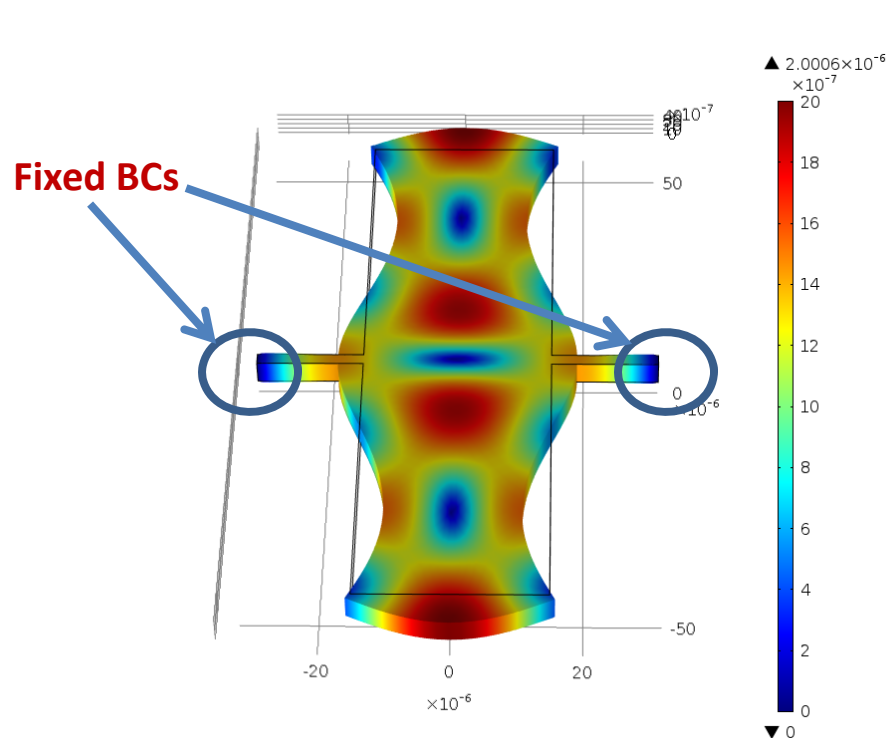
**Mode shape of the Third Lateral Bulk Mode at 118MHz**



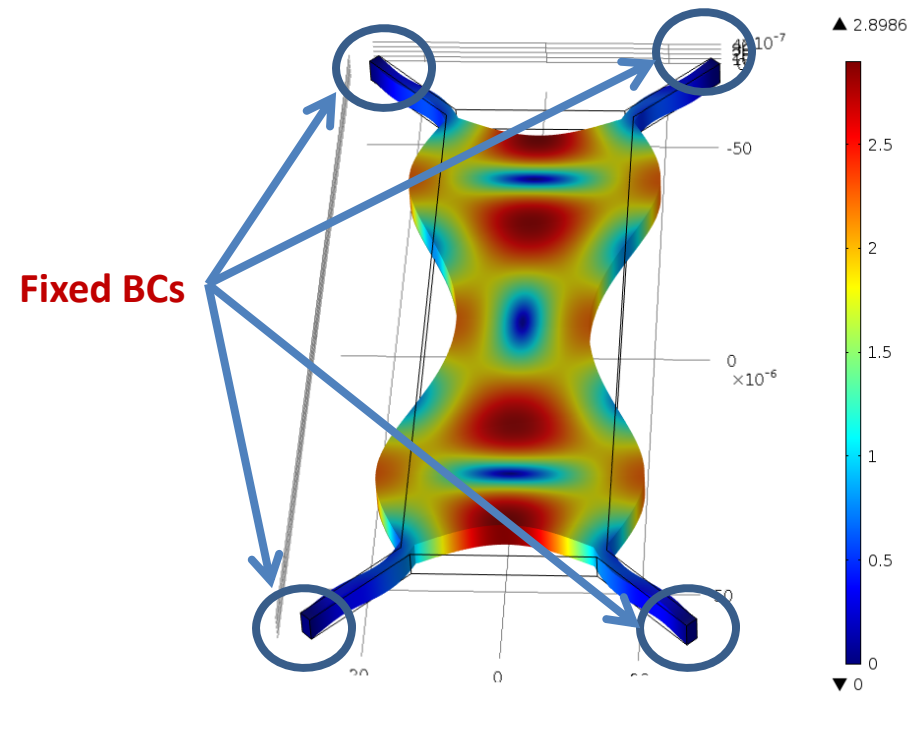
**Meshed Model**

# Anchoring Strategies

- In the Anchor Type I the anchors are attached using the central part of the structure as the anchor point
- The modified anchoring attaches the anchors to the corners of the structure
- **The main idea is to anchor the resonator at places of minimum displacement**



**Mode shape for the Anchor Type I**



**Mode shape for the Anchor Type II**



# Matched Layers

- **Anchor loss** is modeled using **matched layers (MLs)** that emulate the large expanse of the substrate

- The ML material parameters:-

**Young's Modulus**

$$E' = jE / \alpha$$

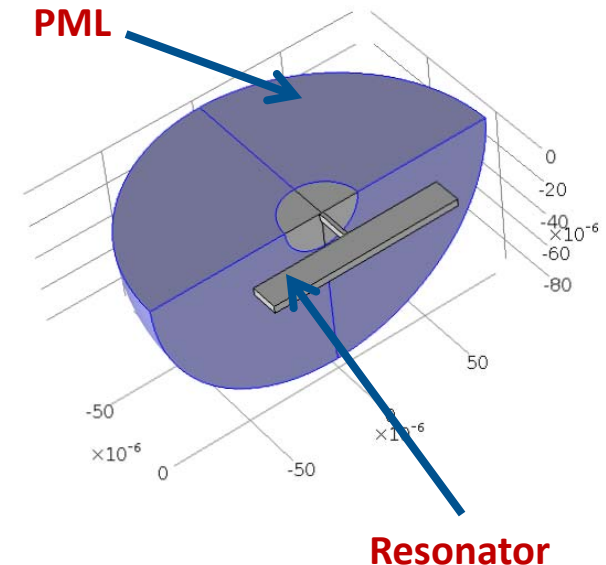
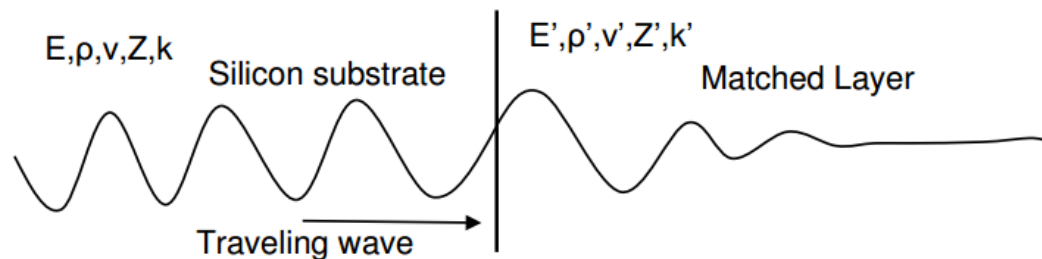
**Density**

$$\rho' = -j\alpha\rho$$

**Poisson's Ratio**

$$\nu' = \nu$$

( E, ρ and ν : parameters of the resonator material)

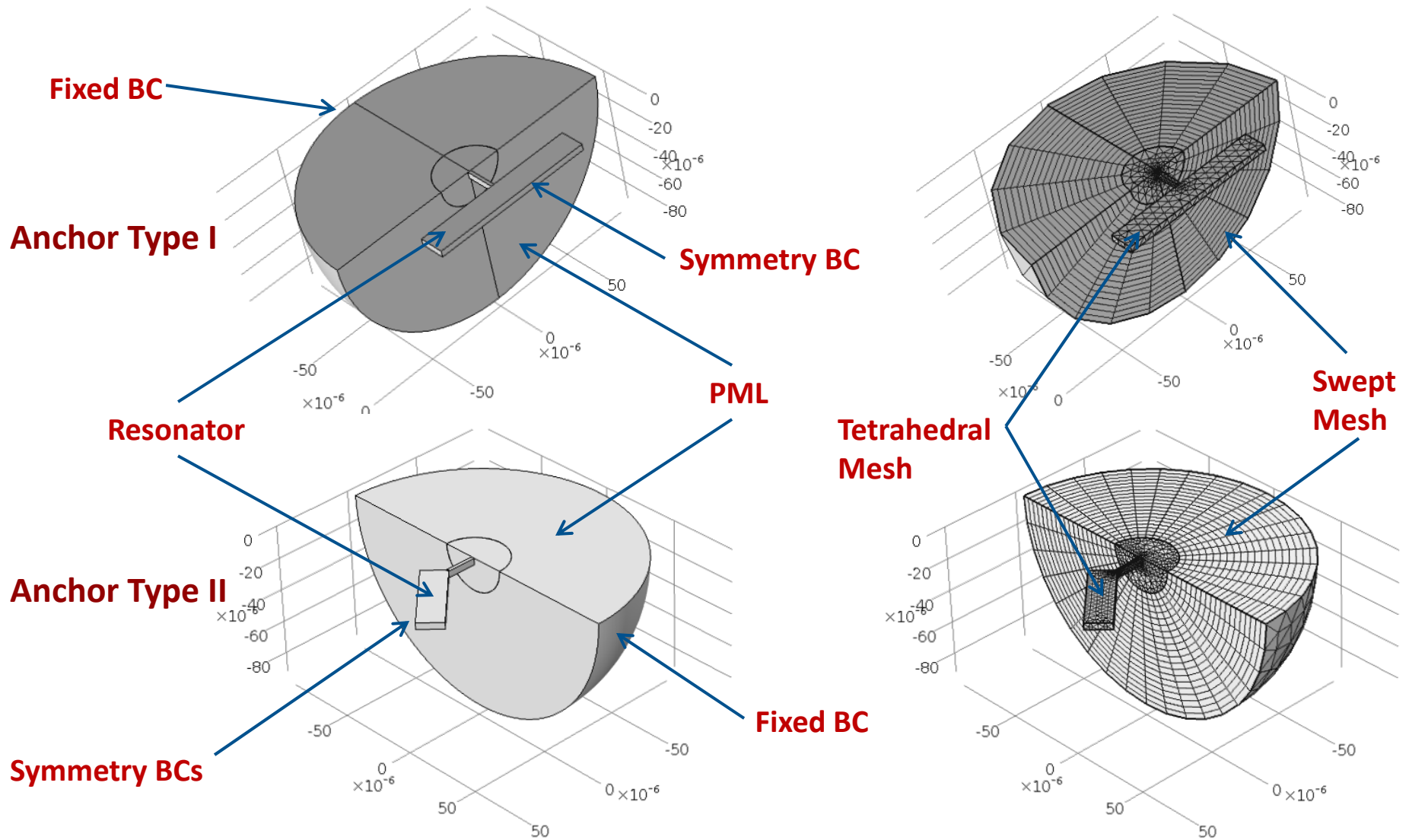


- COMSOL implements **Perfectly Matched Layers** through complex co-ordinate stretching:-

$$t' = \left( \frac{t}{\Delta_w} \right)^n (1 - i)\lambda F$$

\* P.G.Steeneken et al. ,” **Parameter Extraction and Support-Loss in MEMS Resonators,**” Proc. Comsol Conf. 2007 10/2007.

# FEM Models of the two Resonator Types



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# Stored Energy Density Analysis

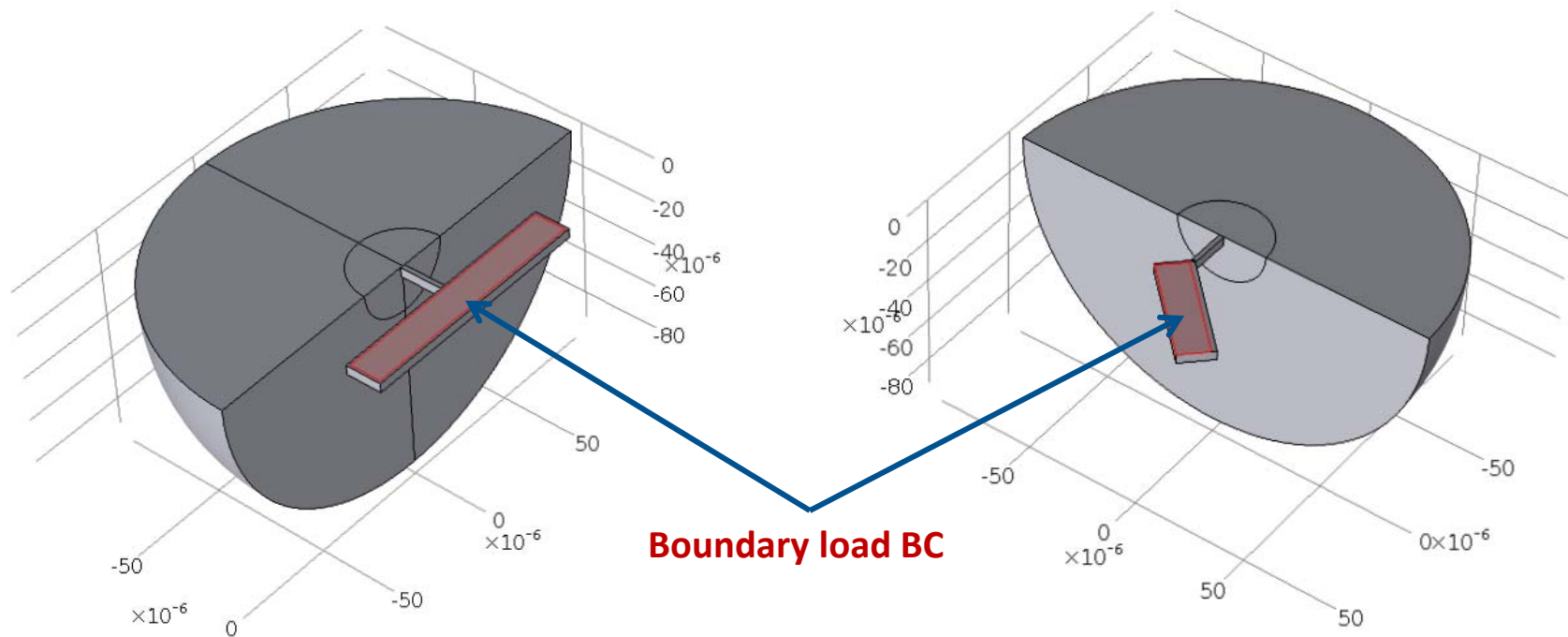
- Stored energy density within the resonator is a measure of the vibrational energy being confined within the resonator
- A higher value of the stored energy Density automatically translates to a higher value of the Quality Factor
- The resonator with the **Anchor Type I** is attached to the substrate at the points of high displacement which results in **a larger amount of acoustic energy leaking into the substrate**
- Conversely in the resonator with **Anchor Type II** the points of anchorage have minimum displacement resulting **in lower leakage of acoustic power**
- The efficacy of Anchor Type II over Anchor type I in terms of the Stored Energy Density is established through simulation

# Stored Energy Density Analysis

- The lateral drive force acting on the resonator is estimated using the relation:-

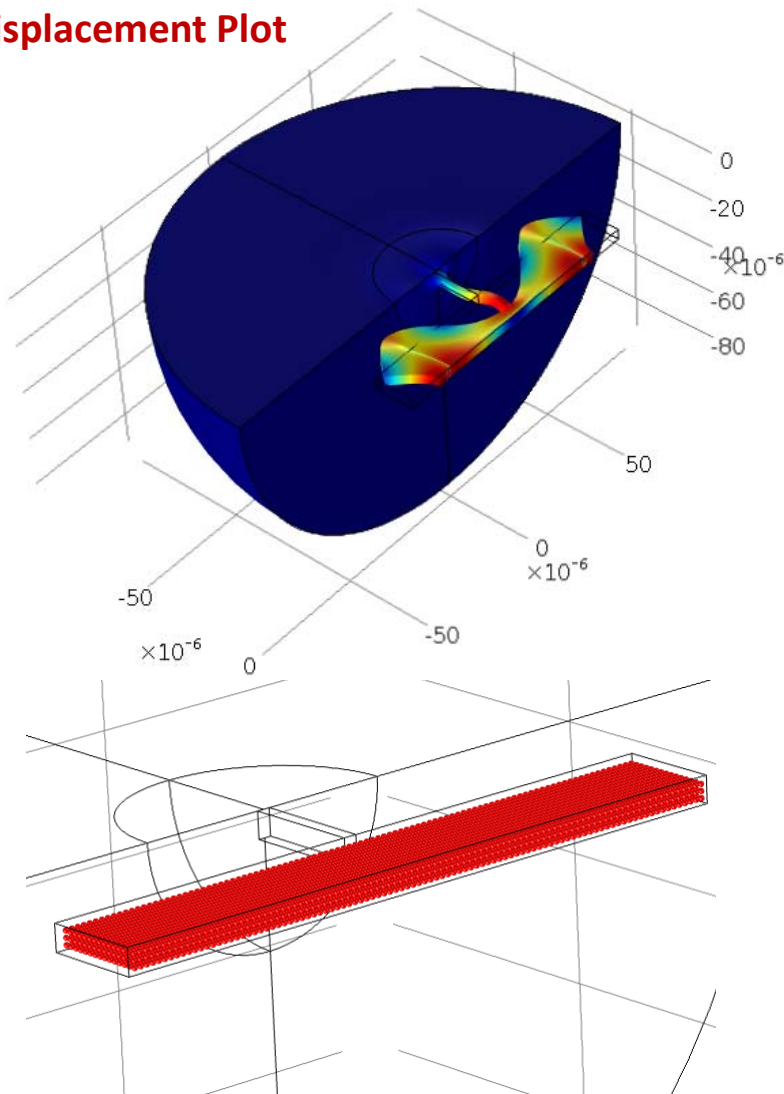
$$f_{drive} = v_{SiN} \cdot V_{DC} \cdot \frac{\epsilon_0 \cdot K_{SiN} \cdot A_{electrode}}{t_{SiN}^2} \cdot v_{ac}$$

- The Boundary Load boundary condition is then applied to the resonator body to get the frequency response of the resonator

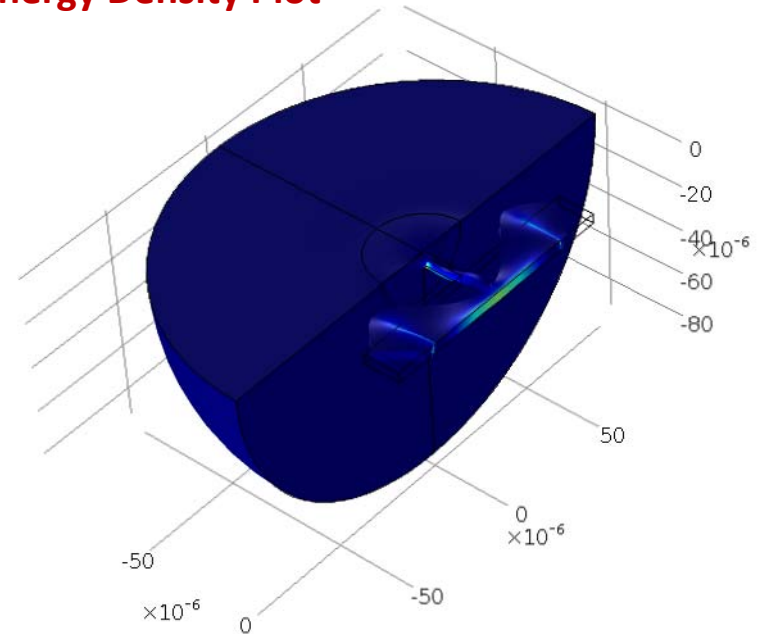


# Stored Energy Density Analysis

Displacement Plot



Stored Energy Density Plot

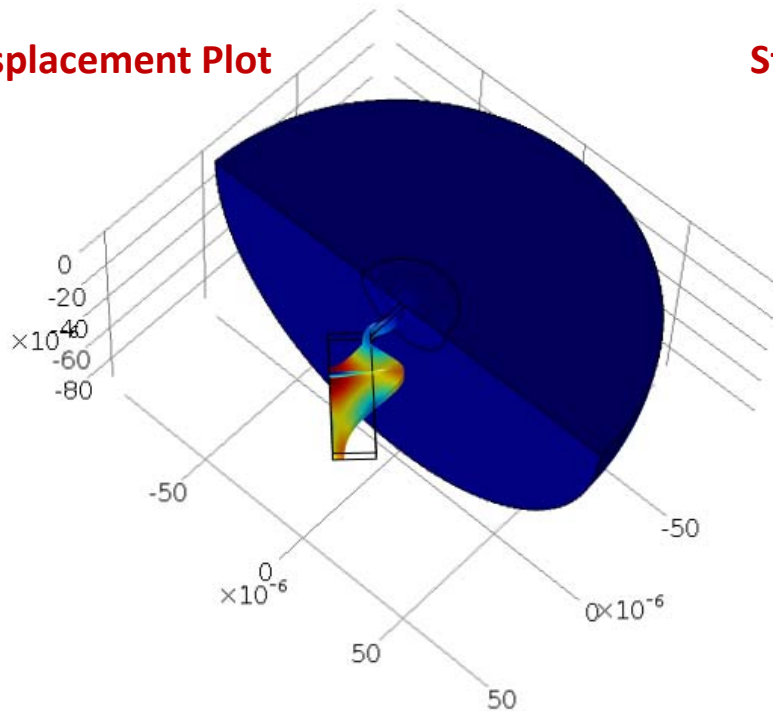


- A new data set with the point grid is created within the resonator volume
- The value of the stored energy density was averaged over these points

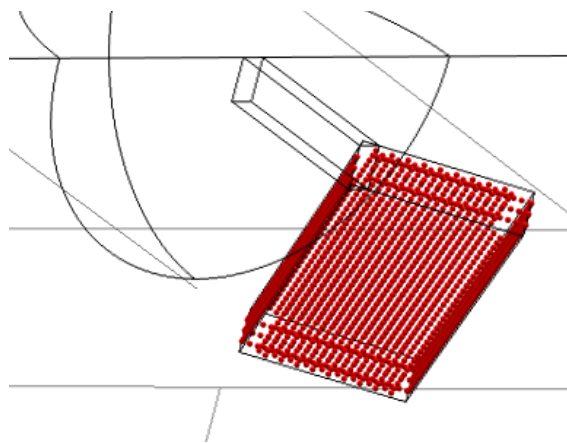
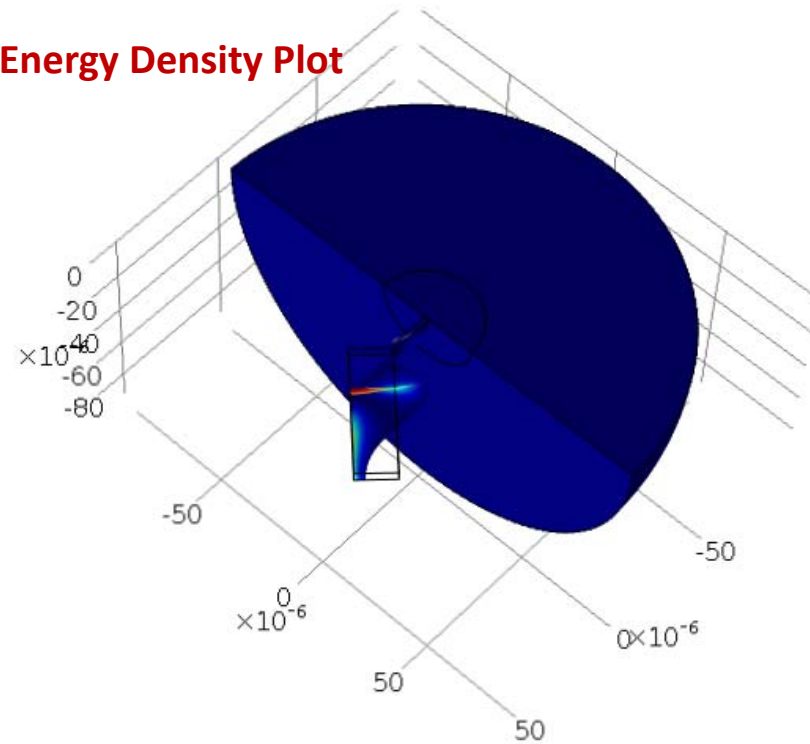
**Stored Energy Density =  $9.025 \times 10^{-4} \text{ J/m}^3$**

# Stored Energy Density Analysis

Displacement Plot



Stored Energy Density Plot



- The same procedure is followed for the Anchor type II as the Anchor type I

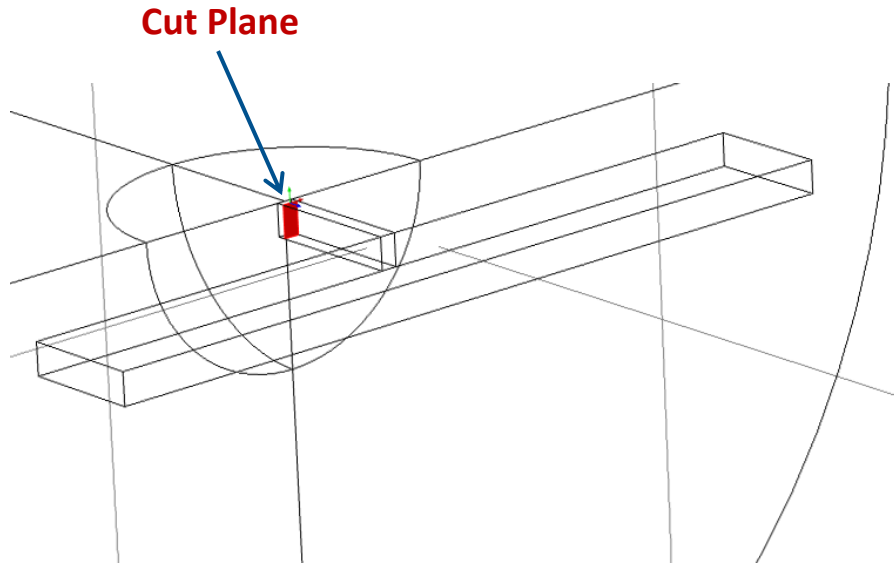
**Stored Energy Density =  $188.9 \times 10^{-4} \text{ J/m}^3$**

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# Leaky Power Analysis

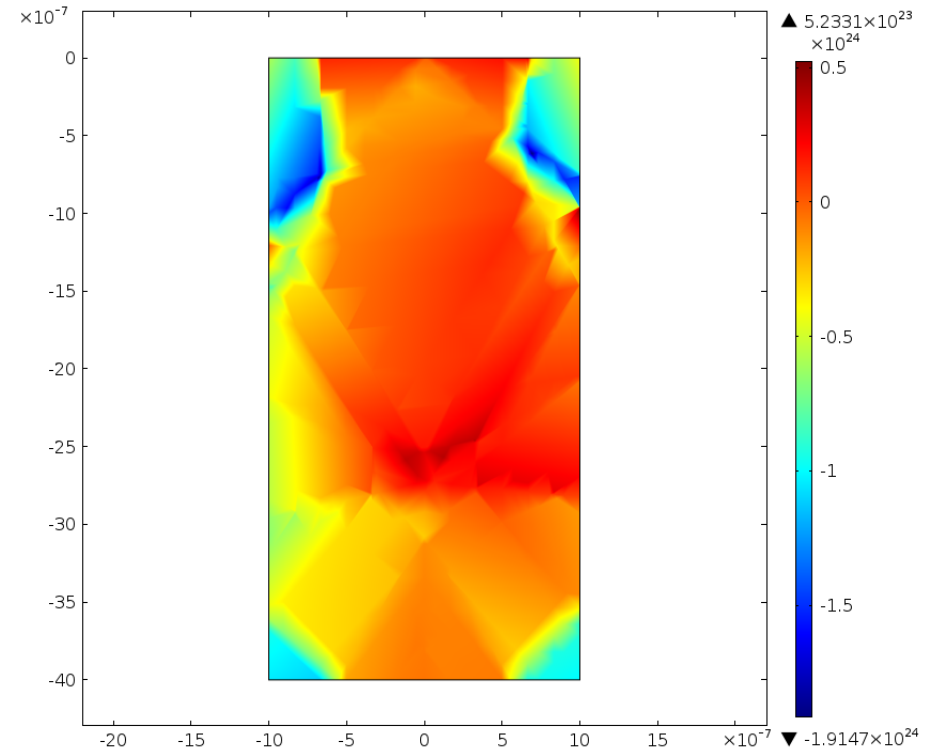
- Leaky Power is used to estimate the **flux of the acoustic energy radiating from the resonator** to the substrate through the anchors
- A higher Leaky Power indicates that the resonator is losing energy to the substrate at a higher rate
- The Leaky Powers of the two anchor types are compared through simulation

# Leaky Power Analysis



- A new dataset is created as a 2D cut plane cutting the anchor at the point where it attaches to the substrate
- The surface average of the mechanical energy flux over the cut plane is evaluated

**Leaky Power Flux=  $0.37545 \text{ W/m}^2$**

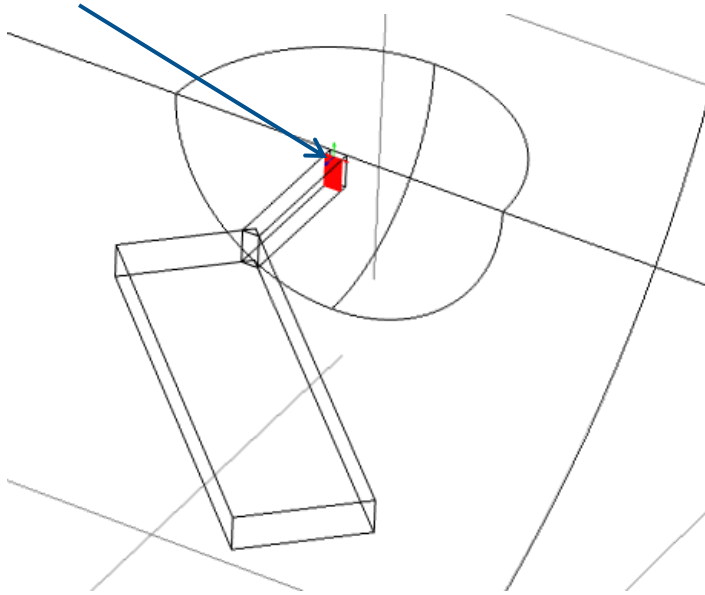


**Surface plot for the normal component of the mechanical energy flux through the anchor**



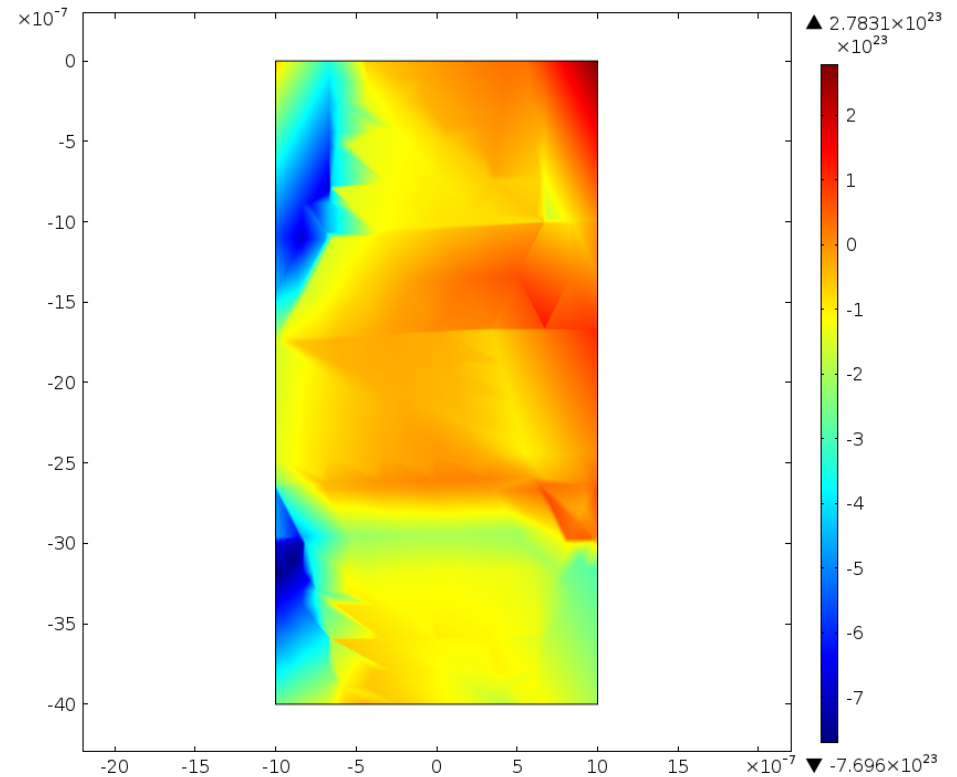
# Leaky Power Analysis

Cut Plane



- Another 2D Cut Plane dataset is created for the second anchor type as depicted above
- The surface average of the mechanical energy flux over the cut plane is evaluated

$$\text{Leaky Power Flux} = 0.13406 \text{ W/m}^2$$



Surface plot for the normal component of the mechanical energy flux through the anchor

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# Quality Factor Evaluation

- Complex coordinate stretching of the PML domain causes the **eigenfrequencies of the of the resonator to also be complex**
- The complex eigenfrequencies reflect the exponential damping of the amplitudes of the displacement field
- The Quality Factor is directly inferred from the eigenfrequency analysis using the relation\*:-

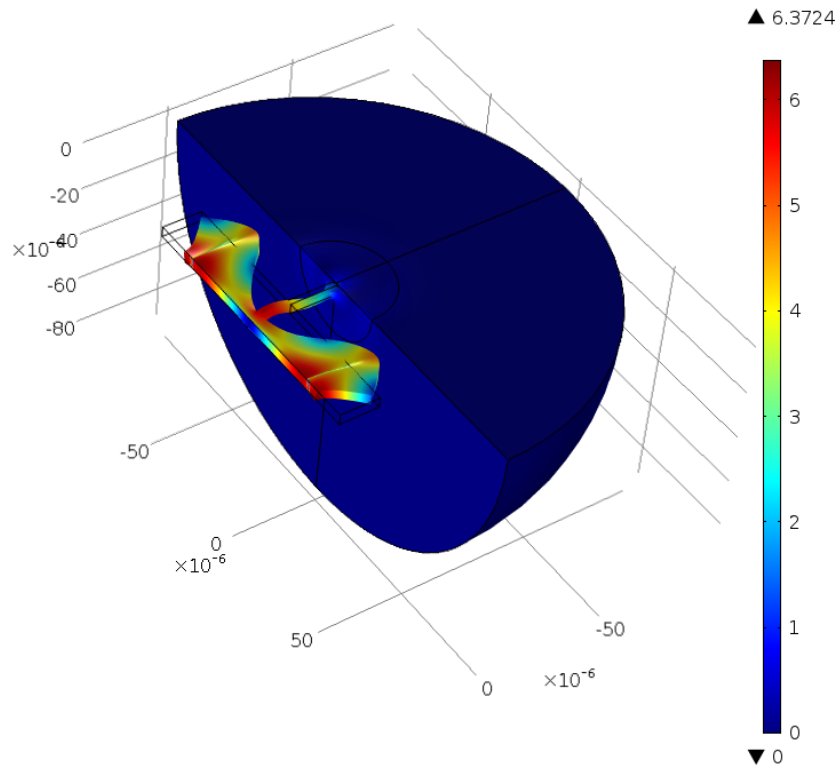
$$Q_i = \frac{\text{Re } \omega_i}{2 \text{Im } \omega_i}$$

- The Quality Factor so evaluated is the one **taking into account only the anchor losses**

\* P.G.Steeneken et al. ,” **Parameter Extraction and Support-Loss in MEMS Resonators,**” Proc. Comsol Conference 2007 10/2007.

# Quality Factor Evaluation

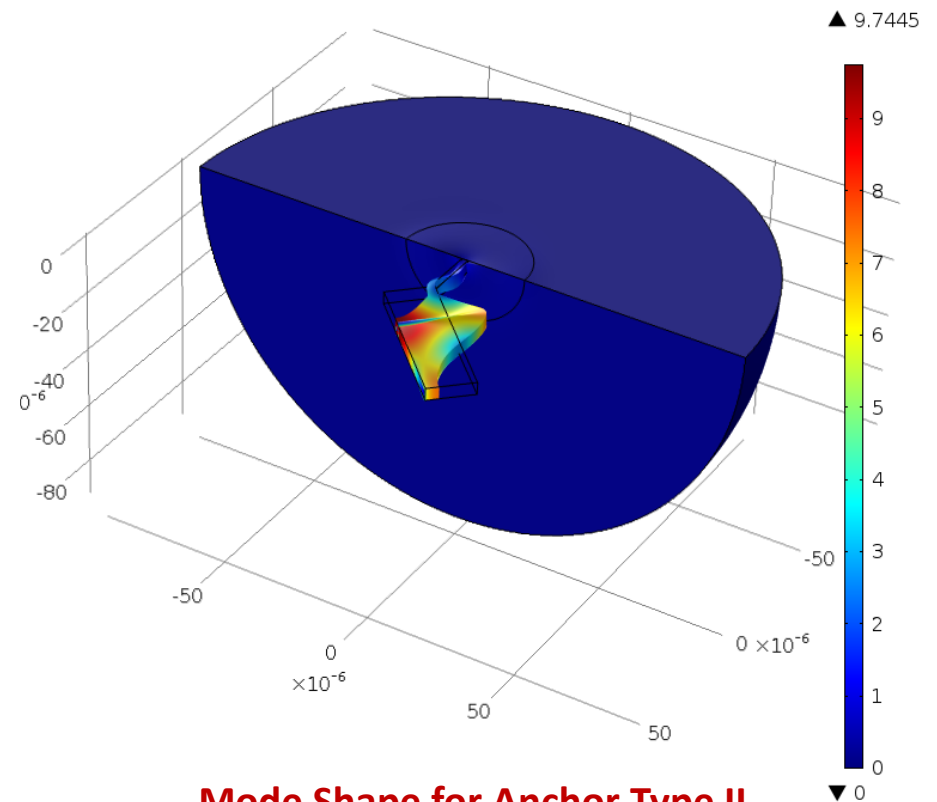
Eigenfrequency= $1.181123e8+1.439842e5i$  Surface: Total displacement (m)



**Mode Shape for Anchor Type I**

**Q Factor = 820**

Eigenfrequency= $1.183997e8+22529.555678i$  Surface: Total displacement (m)



**Mode Shape for Anchor Type II**

**Q Factor = 2527**

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## Summary

- Two different anchor arrangements for a particular target mode shape were considered for comparison
- **PML Method** was adopted to study the anchor losses in the two arrangements
- The performance of Anchor Type II (corner anchored) was found to be better than that of Anchor Type I (side anchored) in terms of the metrics such as:-
  - **Stored Energy Density** : Higher for Anchor Type II
  - **Leaky Power** : Higher for Anchor type I
- The performance disparity between the two anchor types was further verified by evaluating the **Quality Factor** from the eigenfrequency analysis results

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# THANK YOU

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